TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ($L^2-\pi$ -MOSV)

2SK2391

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4 V gate drive

• Low drain-source ON resistance $: RDS(ON) = 66 \text{ m}\Omega \text{ (typ.)}$

• High forward transfer admittance $|Y_{fs}| = 16 \text{ S (typ.)}$

• Low leakage current $I_{DSS} = 100 \,\mu\text{A} \,(\text{max}) \,(\text{V}_{DS} = 100 \,\text{V})$

• Enhancement-mode : $V_{th} = 0.8 \sim 2.0 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	100	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	100	V	
Gate-source voltage		V_{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	20	Α	
	Pulse (Note 1)	I _{DP}	80	Α	
Drain power dissipatio	n (Tc = 25°C)	P_{D}	35	W	
Single pulse avalanche energy (Note 2)		E _{AS}	208	mJ	
Avalanche current		I _{AR}	20	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	3.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Weight: 1.9 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.57	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25 °C (initial), L = 840 μ H, R_{G} = 25 Ω , I_{AR} = 20 A

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device.

Please handle with caution.

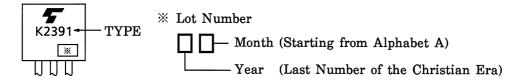
Electrical Characteristics (Ta = 25°C)

Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	_	V
Gate threshold v	oltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		RDS (ON)	V _{GS} = 4 V, I _D = 10 A	_	0.09	0.13	Ω
		R _{DS} (ON)	V _{GS} = 10 V, I _D = 10 A	-	0.066	0.085	
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 10 A	8	16	_	S
Input capacitano	e	C _{iss}		_	1100	_	pF
Reverse transfe	r capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	180	_	
Output capacitance		C _{oss}		_	400	_	
Switching time	Rise time	t _r	$V_{GS} = 10 \text{ V}$ V_{OUT} $R_{L} = 5 \Omega$ $V_{DD} = 50 \text{ V}$		20	_	
	Turn-on time	t _{on}		l	30		ns
	Fall time	t _f		l	50		115
	Turn-off time	t _{off}	Duty \leq 1%, t _w = 10 μ s		140	_	
Total gate charge (Gate-source plus gate-drain)		Qg	V _{DD} ≈ 80 V, V _{GS} = 10 V, I _D = 27 A		50		nC
Gate-source charge		Q _{gs}		_	34	_	
Gate-drain ("miller") charge		Q _{gd}			16	_	

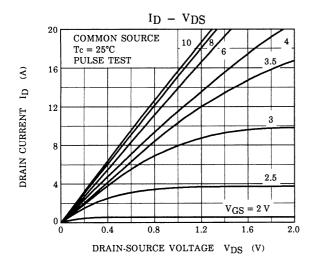
Source-Drain Ratings and Characteristics (Ta = 25°C)

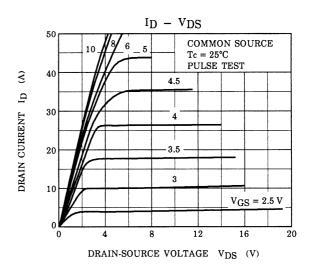
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	20	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	80	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 20 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I_{DR} = 20 A, V_{GS} = 0 V, dI_{DR} / dt = 50 A / μ s	_	155	_	ns
Reverse recovery charge	Q _{rr}		_	0.31	_	μC

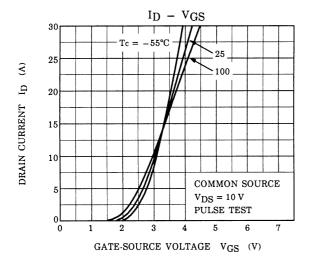
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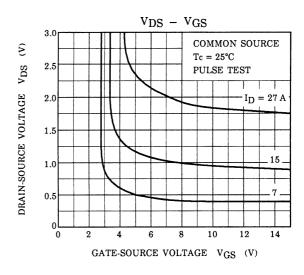


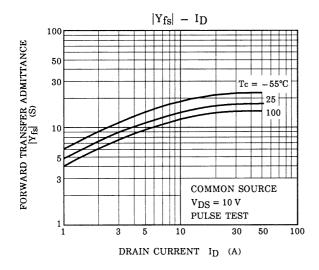
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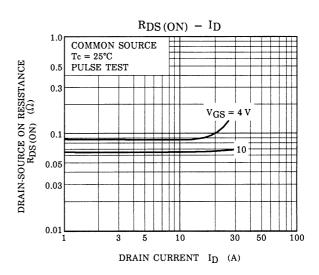




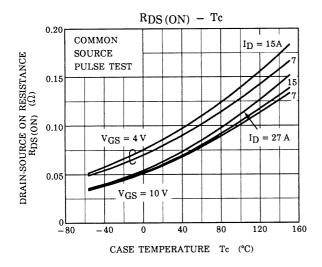


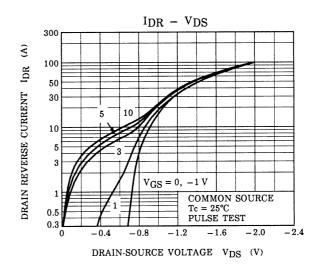


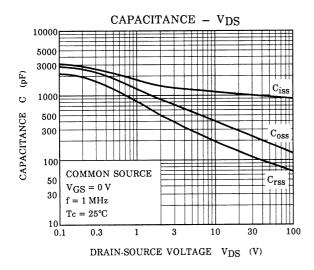


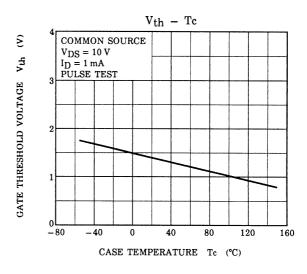


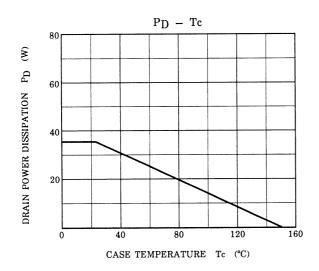
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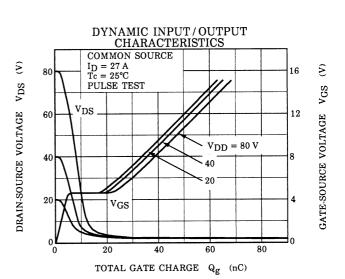




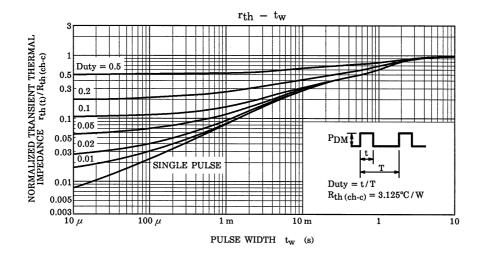


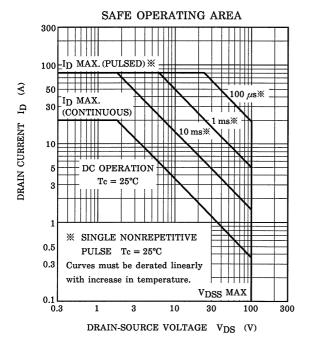


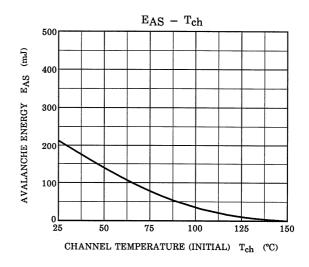


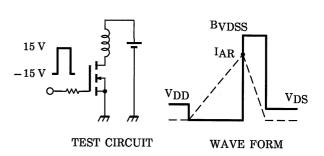


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$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 25~V,~L = 840~\mu H \end{aligned} \qquad EAS &= \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right) \end{aligned}$$

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